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Laterally Resolved Neutron Depth Profiling with the N4DP Instrument

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Neutron Depth Profiling (NDP) is a non-destructive, element-specific, high-resolution nuclear analytical technique, which is often used to probe concentration profiles of lithium, boron, nitrogen, helium and several other light elements in different host materials. The N4DP instrument is located at the Prompt Gamma Activation Analysis (PGAA) beam line of Heinz Maier-Leibnitz Zentrum (MLZ), which provides a cold neutron flux up to $5 \times 10^{10} \text{ s}^{-1} \text{ cm}^{-2}$.

We applied NDP to study the lithium-ion concentration gradient in energy storage systems, e.g. Li-ion batteries. Here, NDP reveals the evolution of immobilized lithium, which is one of the main causes of battery lifetime limitation. Furthermore, the status of the ongoing development towards 4D profiling is presented, where not only the concentration gradient, but also the lateral position of probes as well as its time evolution will be measured. For this, a highly segmented Si-based detector with 32×266 stripes, including integrated, self-triggering electronics, were successfully assessed. Using a camera-obscure geometry setup, we aim for lateral scanning with a space resolutions down to $100 \mu\text{m} \times 100 \mu\text{m}$ and highest time resolutions using a newly developed elliptical focusing neutron guide. This project is supported by the BMBF, Contract No. 05K16WO1, 05K19WO8.

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